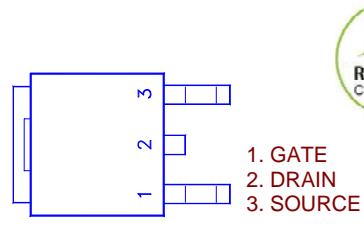
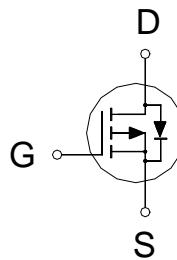


**NIKO-SEM**
**P-Channel Enhancement Mode  
Field Effect Transistor**
**PD537BA**  
TO-252  
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-30V	8mΩ	-71A

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 25$	V
Continuous Drain Current <sup>2</sup>	$I_D$	-71	A
		-45	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	-160	A
Avalanche Current	$I_{AS}$	-36	
Avalanche Energy	$E_{AS}$	64.8	mJ
Power Dissipation	$P_D$	73	W
		29	
Junction & Storage Temperature Range	$T_J, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.7	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Package limitation current is -55A.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1	-1.6	-3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 25V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V$			-1	$\mu\text{A}$
		$V_{DS} = -20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			-10	

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Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -20A		6.5	8	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -20A		9.6	14	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -20A		49		S
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = -15V, f = 1MHz		2464		pF
Output Capacitance	C <sub>oss</sub>			374		
Reverse Transfer Capacitance	C <sub>rss</sub>			271		
Gate Resistance	R <sub>g</sub>		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V, f = 1MHz	3.8		Ω
Total Gate Charge <sup>2</sup>	Q <sub>g</sub> (V <sub>GS</sub> =-10V)	V <sub>DS</sub> = -15V, I <sub>D</sub> = -20A		55		nC
	Q <sub>g</sub> (V <sub>GS</sub> =-4.5V)			27		
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>			8.3		
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>			11		
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>			15		nS
Rise Time <sup>2</sup>	t <sub>r</sub>		V <sub>DS</sub> = -15V ,	20		
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>		I <sub>D</sub> ≈ -20A, V <sub>GS</sub> = -10V, R <sub>GEN</sub> = 6Ω	41		
Fall Time <sup>2</sup>	t <sub>f</sub>			23		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>J</sub> = 25 °C)</b>						
Continuous Current <sup>3</sup>	I <sub>S</sub>				-56	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = -20A, V <sub>GS</sub> = 0V			-1.3	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = -20A, dI <sub>F</sub> /dt = 100A / μS		26		nS
Reverse Recovery Charge	Q <sub>rr</sub>			13		nC

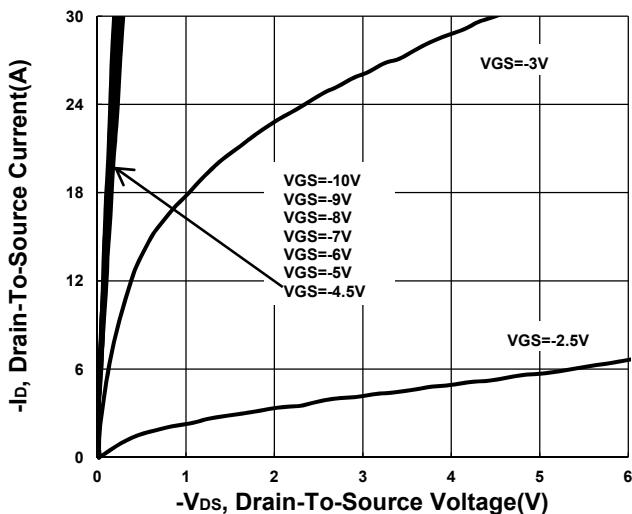
<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.<sup>3</sup>Package limitation current is -55A.

**NIKO-SEM**

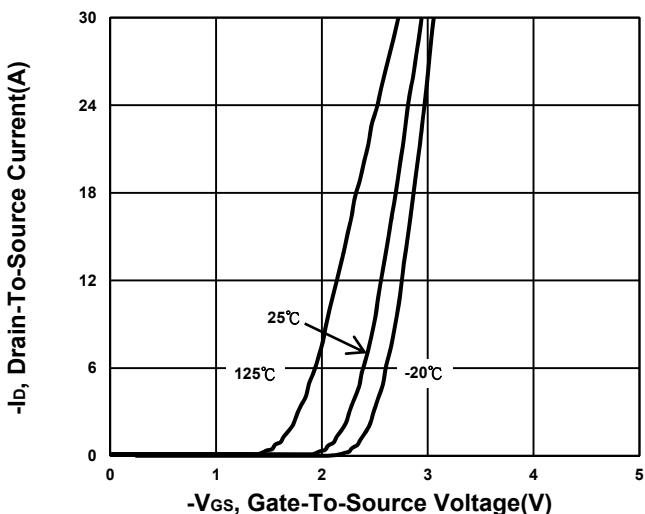
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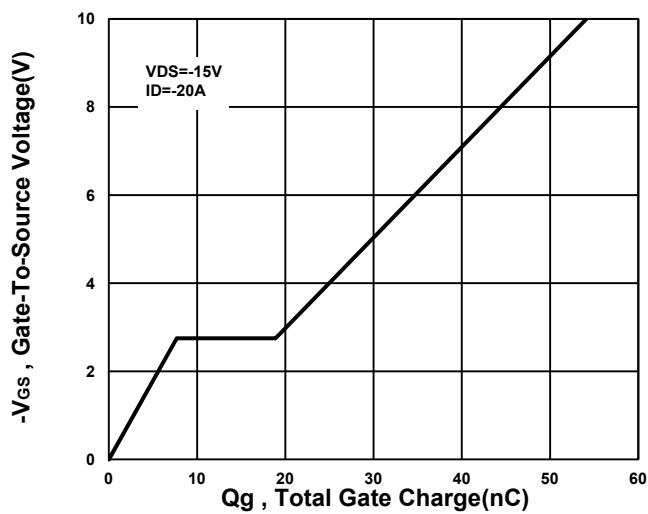
**Output Characteristics**



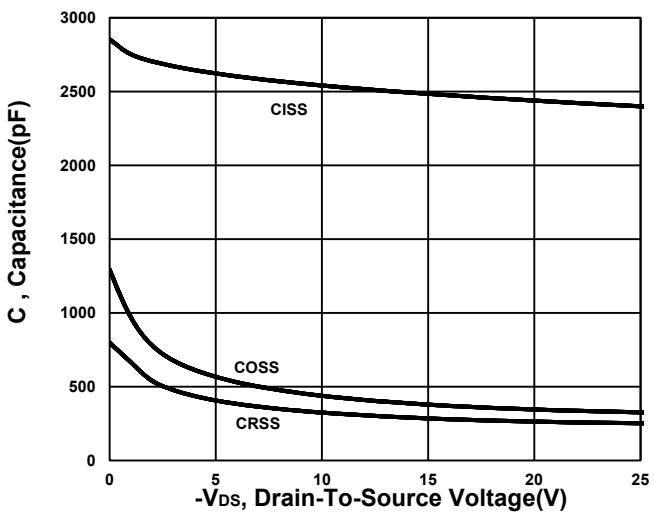
**Transfer Characteristics**



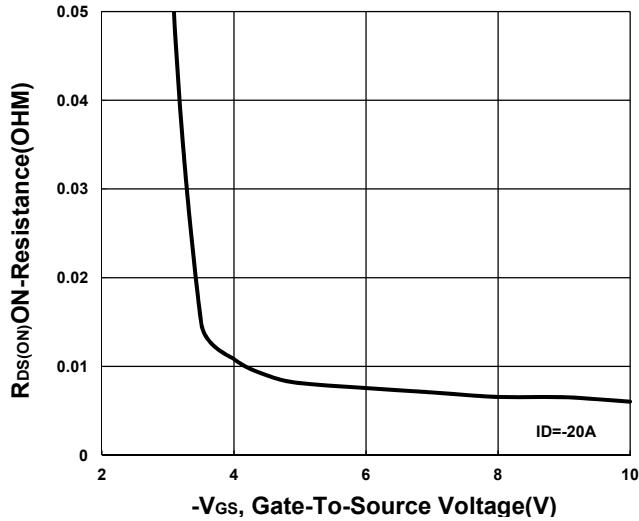
**Gate charge Characteristics**



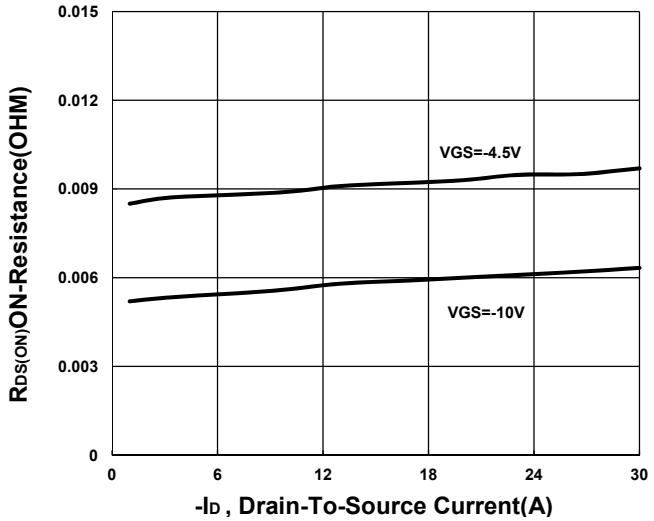
**Capacitance Characteristic**



**On-Resistance VS Gate-To-Source**



**On-Resistance VS Drain Current**



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